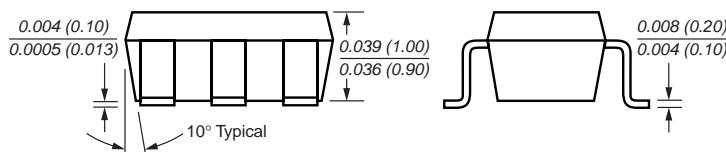
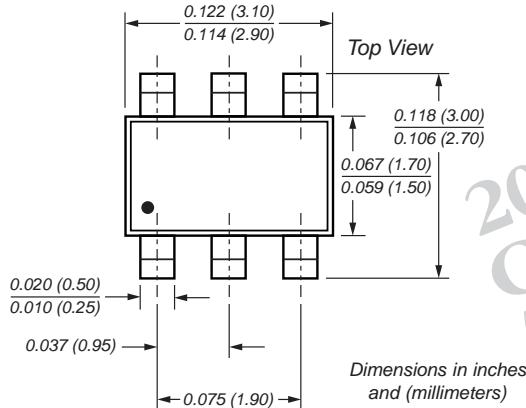




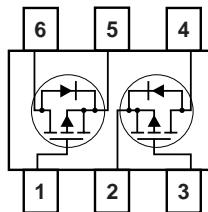
Dual P-Channel Logic Level Enhancement-Mode MOSFET

SOT-23-6L

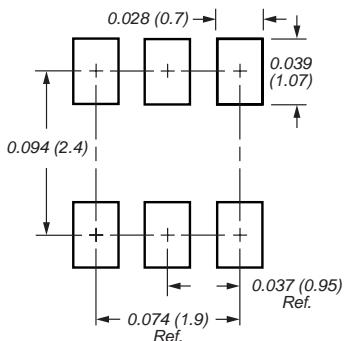
V_{DS} -20V
R_{DSON} 0.135Ω
I_D -2.3A



Pin Configuration (Top View)



Mounting Pad Layout



Mechanical Data

Case: SOT-23-6L package

Terminals: Leads solderable per MIL-STD-750,
Method 2026

Marking Code: M3

Features

- Advanced trench process technology
- High density cell design for ultra low on-resistance
- Popular SOT-23-6L package with copper lead-frame for superior thermal and electrical capabilities
- Compact and low profile
- 1.8V rated

Maximum Ratings and Thermal Characteristics ($T_A = 25^\circ\text{C}$ unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V _{DS}	-20	V
Gate-Source Voltage	V _{GS}	±8	
Continuous Drain Current ⁽²⁾ $T_J = 150^\circ\text{C}$	I _D	-2.3 -1.8	A
Pulsed Drain Current ⁽¹⁾	I _{DM}	-8	
Maximum Power Dissipation ⁽²⁾	P _D	1.15 0.73	W
Operating Junction and Storage Temperature Range	T _J , T _{stg}	-55 to 150	°C
Junction-to-Ambient Thermal Resistance ⁽²⁾	R _{θJA}	110	°C/W

Note: (1) Pulse width limited by maximum junction temperature.

(2) Surface mounted on a 1in² 2oz. Cu PCB (FR-4 material)

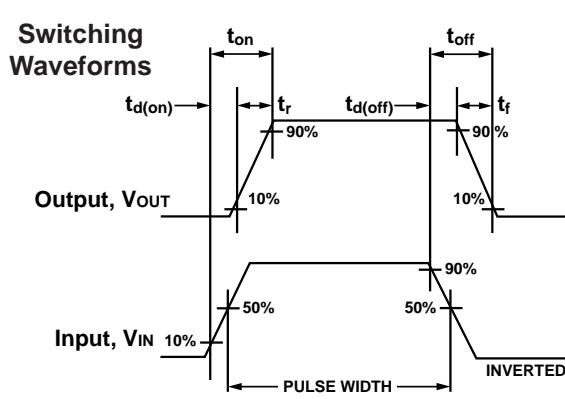
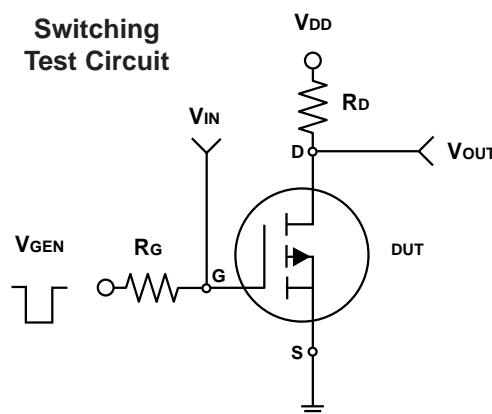
Electrical Characteristics (T_J = 25°C unless otherwise noted)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Static						
Drain-Source Breakdown Voltage	BVDSS	V _{GS} = 0V, I _D = -250μA	-20	-	-	V
Breakdown Voltage Temp. Coefficient	ΔBVDSS/ΔT _J	Reference to 25°C, I _D =-1mA	-	-8.8	-	mV/°C
Gate Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = -250μA	-0.45	-	-	V
Gate-Body Leakage	I _{GSS}	V _{GS} = ±8V, V _{DS} = ±0V	-	-	±100	nA
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = -16V, V _{GS} = 0V	-	-	-1	μA
		V _{DS} = -16V, V _{GS} = 0V, T _J =85°C	-	-	-10	
On-State Drain Current ⁽¹⁾	I _{D(on)}	V _{DS} ≥ -5V, V _{GS} = -4.5V	-5	-	-	A
Drain-Source On-State Resistance ⁽¹⁾	R _{D(on)}	V _{GS} = -4.5V, I _D = -2.3A	-	109	135	mΩ
		V _{GS} = -2.5V, I _D = -2.0A	-	146	180	
		V _{GS} = -1.8V, I _D = -1.7A	-	205	250	
Forward Transconductance ⁽¹⁾	g _{fs}	V _{DS} = -5V, I _D = -2.3A	-	5	-	S
Dynamic						
Total Gate Charge ⁽¹⁾	Q _g	V _{DS} = -10V, V _{GS} = -4.5V I _D = -2.3A	-	5.1	7.5	nC
Gate-Source Charge ⁽¹⁾	Q _{gs}		-	1.0	-	
Gate-Drain Charge ⁽¹⁾	Q _{gd}		-	1.2	-	
Turn-On Delay Time ⁽¹⁾	t _{d(on)}	V _{DD} = -8V, R _L = 8Ω I _D ≈ -1A, V _{GEN} = -4.5V R _G = 6Ω	-	7	20	ns
Turn-OnRise Time ⁽¹⁾	t _r		-	45	60	
Turn-Off Delay Time ⁽¹⁾	t _{d(off)}		-	162	200	
Turn-OffFall Time ⁽¹⁾	t _f		-	116	160	
Input Capacitance	C _{iss}	V _{DS} = -10V, V _{GS} = 0V f = 1.0MHz	-	343	-	pF
Output Capacitance	C _{oss}		-	77	-	
Reverse Transfer Capacitance	C _{rss}		-	58	-	
Source-Drain Diode						
Maximum Diode Forward Current	I _S	T _A = 25°C	-	-	-1.3	A
Maximum Pulsed Diode Forward Current ⁽²⁾	I _{SM}	—	-	-	-8	A
Diode Forward Voltage ⁽¹⁾	V _{SD}	V _{GS} = 0V, I _S = -1.05A	-	-0.85	-1.1	V

Notes:

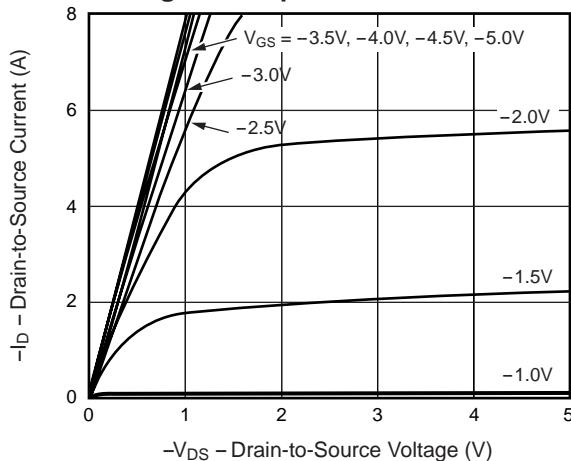
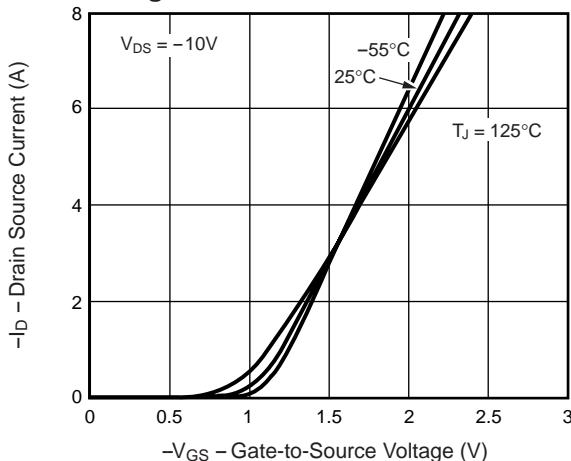
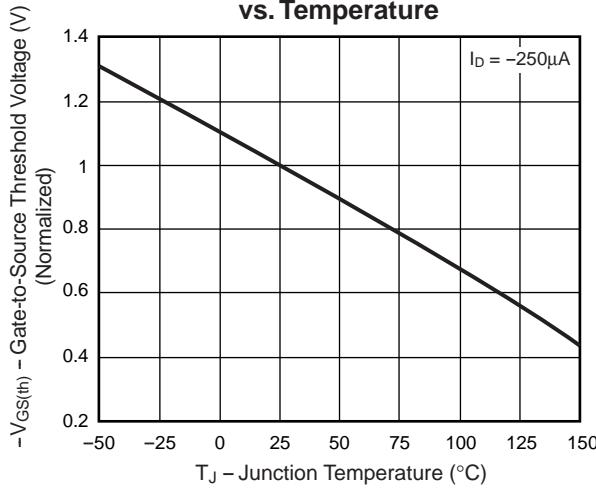
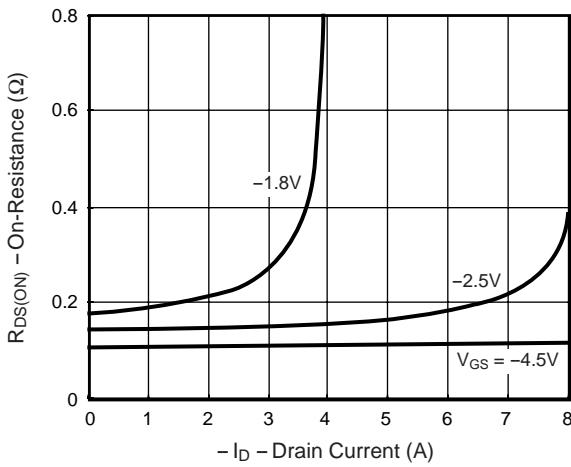
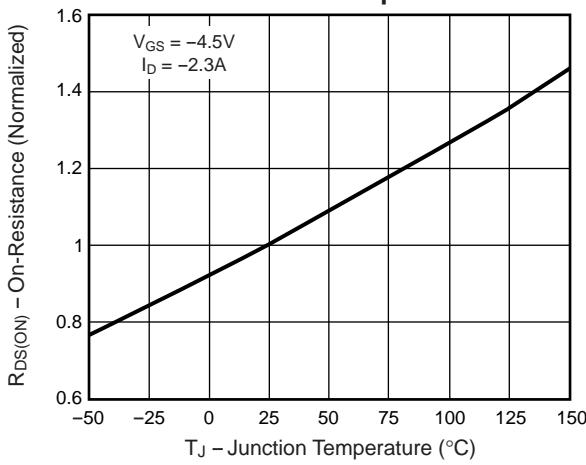
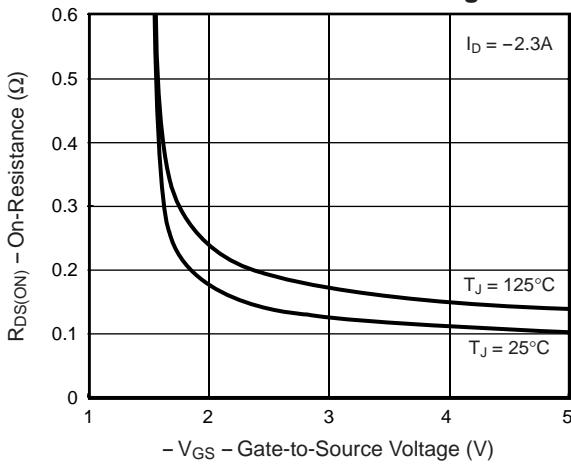
(1) Pulse test; pulse width ≤ 300μs, duty cycle ≤ 2%

(2) Pulse width limited by maximum junction temperature



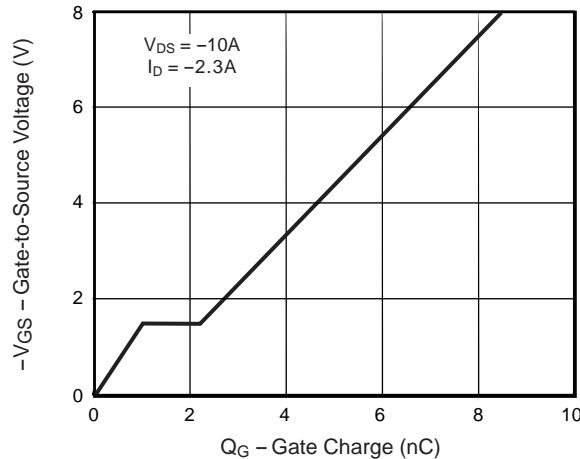
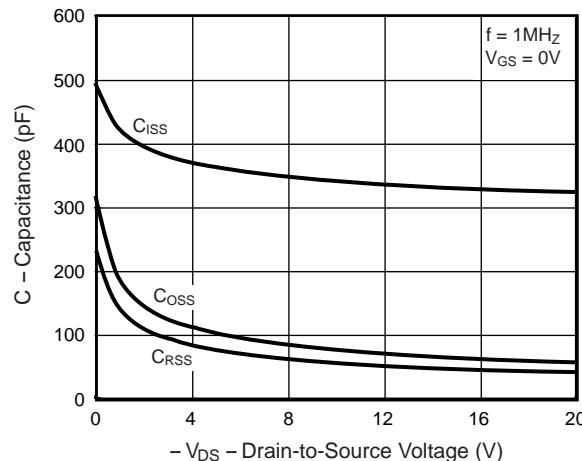
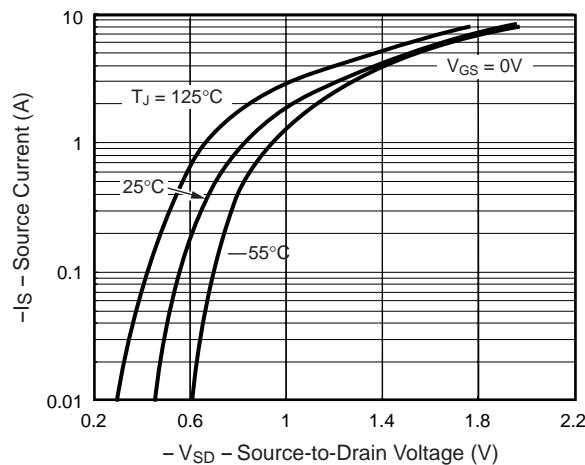
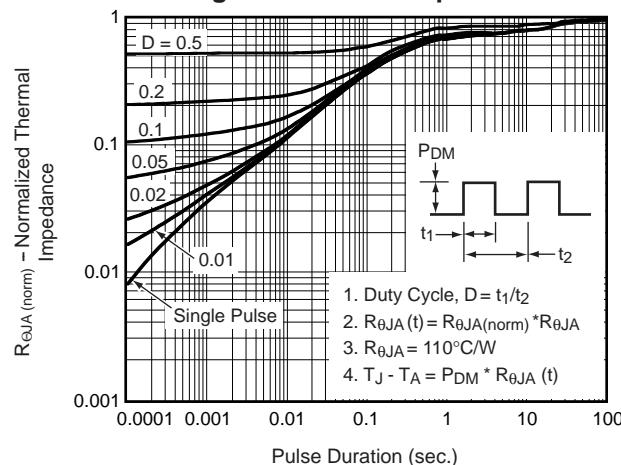
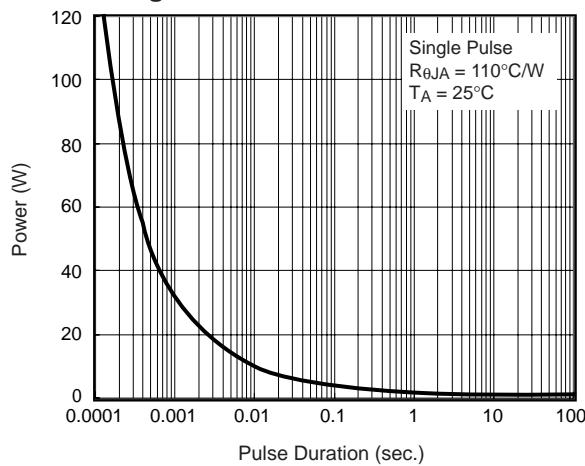
Ratings and Characteristic Curves

($T_A = 25^\circ\text{C}$ unless otherwise noted)

Fig. 1 – Output Characteristics

Fig. 2 – Transfer Characteristics

Fig. 3 – Threshold Voltage vs. Temperature

Fig. 4 – On-Resistance vs. Drain Current

Fig. 5 – On-Resistance vs. Junction Temperature

Fig. 6 – On-Resistance vs. Gate-to-Source Voltage


Ratings and Characteristic Curves

($T_A = 25^\circ\text{C}$ unless otherwise noted)

Fig. 7 – Gate Charge**Fig. 8 – Capacitance****Fig. 9 – Source-Drain Diode Forward Voltage****Fig. 10 – Thermal Impedance****Fig. 11 – Power vs. Pulse Duration****Fig. 12 – Maximum Safe Operating Area**